Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	, ,
10/773,629	KRISHNAN ET AL.	
Examiner	Art Unit	
JOHN J. LEE	2684	

JOHN J. LEE

SEARCHED				
Class	Subclass	Date	Examiner	
455	134 139 67.13 67.13 67.11 136 134 135 139	7/24/2006	J.L	
370	337 370	7/24/2006	J.L	
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